

### A SURVEY OF RESEARCH ON MACHINE LEARNING FOR TEST-BASED VERIFICATION

Dr Chris Bennett

9th April 2025





### Background

- Test-Based Functional Verification is a process to establish a design carries out functions according to its specification.
- Coverage points (CPs) analogous to named states of a design
- Challenge is to choose the inputs to hit all specified coverage points using minimal resources —> use machine learning



# Part of a bigger picture

- Functional verification using MLbased dynamic (test) methods for micro-electronic designs
- Research increasing...but most ML test-techniques not adopted
  - What actions are needed to make better use of existing techniques
  - Lessons for research into new techniques



### Sourcing the data



<sup>1</sup>Fontes, A., & Gay, G. (2023). The integration of machine learning into automated test generation: A systematic mapping study. Software Testing, Verification and Reliability

### **Historical trends**

- In research for 25 years+
- We include Evolutionary Algorithms



### Techniques by year and type

- Interest in techniques changes
- Use of ML lags other areas?



#### Cumulative sum of research using ML for testbased verification

<sup>1</sup>Fontes, A., & Gay, G. (2023). The integration of machine learning into automated test generation: A systematic mapping study. Software Testing, Verification and Reliability

### Lots of research but low adoption

- Reason one: using ML to map coverage to test stimuli is difficult:
  - Lack of
    - > positive training examples
    - > distance metrics in coverage space and test space
    - > enough positive training examples
  - Stimuli and micro-architecture behaviour at different abstraction levels
  - Design changes alter the ground truth relationships

# A variety of techniques used

- Algorithm types
  - Supervised: input-output pairs
  - Unsupervised: patterns in data
  - Reinforcement: trial and feedback
  - Evolutionary: optimising sets of inputs
- Training methodologies
  - Online: update model after every simulation
  - Offline: train once with historical results
  - Hybrid: bootstrap with historical results and update model regularly



### Count of research by algorithm type



Count of research by training method

# Lots of research but low adoption

- Reason one: using ML to map coverage to test stimuli is difficult:
  - Lack of
    - > positive training examples
    - > distance metrics in coverage space and test space
    - > enough positive training examples
  - Stimuli and micro-architecture behaviour at different abstraction levels
  - Design changes alter the ground truth relationships
- Reason two: too much choice has created a confusing landscape for practitioners —> classify research to aid adoption of ML techniques

### How ML modifies a typical testbench

- All research in this area aims to increase verification efficiency
- Engineers time, simulation time...



### How ML modifies a typical testbench

- Human expert is now free to do other tasks?
- Research needed to make ML test-techniques easier to deploy and maintain



# **Classifying research by test controller**

Test Generation: ML is trained to generate a test



**Test Direction:** the ML is trained to "direct" something else to generate the tests. Usually, by parameterising a constrained random test generator.



### Test Selection: the ML chooses from pre-generated tests



- Set Optimisation choose a subset of tests, often offline
- **Test Filtering** decide to simulate a test on a case-by-case basis, often online
- Prioritisation decide order to run tests

### **Classifying research by test controller**

- Compared to other domains, there is no "right" ML approach
- ...then there's the choice of ML type (supervised, RL...) and algorithm (random forest, ANN, Q-learning....)

	Control over test content	Domain knowledge	Integration complexity
Generation	Direct	High	In the loop
Direction	In-direct	Low	In-direct
Selection	None	Low to None	None



Number of papers by controller type

### **Evaluation baselines and metrics**

Comparing techniques requires common baselines and metrics

60



20 application performance #DUT inputs #DUT inputs ml overhead ml overhead

Metrics by appearances in research

### **Evaluation designs**



- Variety: Shows ML testtechniques are widely applicable
- Number: reflects individual motivations and resources of research
- Types: Unknown, known function, open-source
- Complexity: varies

### Designs used to evaluate techniques

(size of square indicates number seen in research)

# Lots of research but low adoption

- Reason one: using ML to map coverage to test stimuli is difficult:
  - Lack of
    - > positive training examples
    - > distance metrics in coverage space and test space
    - > enough positive training examples
  - Stimuli and micro-architecture behaviour at different abstraction levels
  - Design changes alter the ground truth relationships
- Reason two: too much choice has created a confusing landscape for practitioners -> classify research to aid adoption of ML techniques
- Reason three: high-level problem definition results in research effective at solving uniquely defined problems, but which is difficult to apply and complicates comparisons

# **Opportunities**

### Industry to set the agenda via problem and evaluation criteria

- Maturity and popularity of open designs (e.g., RISC-V)
- Open datasets, pre-configured test benches and coverage models reduce barriers to entry

Researchers to provide better understanding to guide technique selection

- Classification is a first step
- Quantification of resource-performance trade off needed

# **Opportunities**

### Look for synergies in the use of ML

- analogous findings for test-based software verification
- similar applications in wider EDA and beyond



## What could be applied now vs future

Very approximate and unscientific



### Summary

- 25 years of research material exists
- Classifications provide a means to navigate the options
- Industry can define the problem and evaluation criteria
- Research needed on which techniques to apply for a given design
- Look for synergies with the use of ML in wider EDA and beyond



**S** 

**Review of Machine Learning for Micro-Electronic Design Verification** https://arxiv.org/abs/2503.11687

